

ABSTRACT OF THE DISCLOSURE

An interface detection apparatus detects a position of a hidden interface between first and second materials, the first material having a
5 different physical property from the second material. The apparatus encompasses
(a) an irradiation mechanism configured to irradiate an electromagnetic wave
onto a sample implemented by the first and second materials, (b) a detection
mechanism configured to detect the electromagnetic wave that has passed through
the sample, and (c) a traveling mechanism configured to change the relative
10 position of the hidden interface with respect to the position of the detection
mechanism.